Compliant with IEC 62474/ D9.00

MICROCHIP  Semiconductor Device Type: SM (C3X) 008 SOIJ .208in Matte Tin			Termination Base Alloy: Copper Alloy (Cu)			Package Homogeneous Materials: 8.1 Electronics (e.g. pc boards, displays)				JEDEC 97 Product Marking and/or Pkg. Labeling e3
Semiconductor Device Type:	SM	(C3X) 008 SOIJ .208in Matte Tin	% Iotal	1						
Basic Substance	CAS Number	Sub-Component	Weight	mg/part	ppm	99.27	(mg) Total	Mold Compound	% ot Total Weight	79.8
Silica, vitreous	60676-86-0	Mold Compound	69.354	86.277	693,542		Silica, vitreous	60676-86-0	86.91	
Epoxy Resin	Trade Secret	Mold Compound	6.121	7.614	61,207		Epoxy Resin	Trade Secret	7.67	1
Phenolic Resin	Trade Secret	Mold Compound	4.078	5.073	40,778		Phenolic Resin	Trade Secret	5.11	]
Carbon Black	1333-86-4	Mold Compound	0.247	0.308	2,474		Carbon Black	1333-86-4	0.31	
Copper	7440-50-8	Lead Frame	10.031	12.479	100,314			Total	100.00	
Iron	7439-89-6	Lead Frame	0.247	0.307	2,468	13.06	(mg) Total	Lead Frame	% of Total Weight	10.5
Silver	7440-22-4	Lead Frame	0.200	0.249	2,000		Copper	7440-50-8	95.54	
Zinc	7440-66-6	Lead Frame	0.013	0.016	131		Iron	7439-89-6	2.35	
Phosphorous	7723-14-0	Lead Frame	0.009	0.011	87		Silver	7440-22-4	1.91	
Silver (Ag)	7440-22-4	Die Attach	0.563	0.700	5,625		Zinc	7440-66-6	0.13	1
Modified Epoxy Resin	13561-08-5	Die Attach	0.105	0.131	1,050		Phosphorous	7723-14-0	80.0	<u>J</u>
Diglycidylether of bisphenol-F	54208-63-8	Die Attach	0.056	0.070	563			Total	100.00	
Modified Amine	827-43-0	Die Attach	0.026	0.033	263	0.93	(mg) Total	Die Attach	% of Total Weight	0.75
Silicon	7440-21-3	Chip (Die)	7.500	9.330	75,000		Silver (Ag)	7440-22-4	75.00	
Copper	7440-50-8	Wire Bond palladium coated copper (CuPd)	0.197	0.244	1,965		Modified Epoxy Resin	13561-08-5	14.00	1
Palladium	7440-05-3	Wire Bond palladium coated copper (CuPd)	0.004	0.004	35	D	iglycidylether of bisphenol-F		7.50	
Tin	7440-31-5	Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1 hour	1.250	1.555	12,500		Modified Amine	827-43-0	3.50	<u> </u>
TOTALS: 100.000 124.400 1,000,000							Total	100.00		
0.1244 g Total Mass					9.33	Total (mg)	Chip (Die)	% of Total Weight	7.5	
semiconductor device and its homogenous materials comply w and 2002/53/EC (End-of-Life Vehicles (ELV) without exemption		: 2002/95/EC (27 January 2003) & Directive 2011/65/EU (08	June 2011) ar	nd 2015/863/EU	J (31 March					
							Doped Silicon	7440-21-3	100.00	<u> </u>
pliance with the above EU Directives has been verified via interi	nal design contro ubstance is NOT	an intentional ingredient in the semiconductor device and,				0.25	<u> </u>	Total Wire Bond -	100.00	
ppliance with the above EU Directives has been verified via interduce themical substance is absent from the list above, the chemical supported's knowledge and belief as of the date of this document is not below the threshold of regulatory concern for any regulations.	nal design contro ubstance is NOT , there is no credi ory scheme work	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concer 1-wide.	tration of the	chemical subs		0.25	Doped Silicon  (mg) Total	Total		
pliance with the above EU Directives has been verified via interichemical substance is absent from the list above, the chemical srporated's knowledge and belief as of the date of this document is not below the threshold of regulatory concern for any regulating compounds used by Microchip meet the UL94 V0 flammabil	nal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concer 1-wide.	tration of the	chemical subs		0.25	<u> </u>	Total  Wire Bond - Copper, palladium	100.00	
ppliance with the above EU Directives has been verified via interichemical substance is absent from the list above, the chemical stronger is showledge and belief as of the date of this document is not below the threshold of regulatory concern for any regulating compounds used by Microchip meet the UL94 V0 flammabils/lul.com/global/eng/pages/offerings/industries/chemicals/plastic/protective "tubes" in which the specific product is shipped are respective "tubes" in which the specific product is shipped are respective "tubes".	nal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concersi-wide.  Lastics. You can access the UL iQTM family of databases to	tration of the	chemical subs	stance, if	0.25	(mg) Total	Total  Wire Bond - Copper, palladium coated (CuPd)	100.00 % of Total Weight	
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pliance with the above EU Directives has been verified via internemental substance is absent from the list above, the chemical substance is absent from the list above, the chemical supported's knowledge and belief as of the date of this document is not below the threshold of regulatory concern for any regulating compounds used by Microchip meet the UL94 V0 flammabil full.com/global/eng/pages/offerings/industries/chemicals/plastic protective "tubes" in which the specific product is shipped are ruin "reels" may be made from PVC plastic.  The protective "tubes" in which the specific product is shipped are ruin "reels" may be made from PVC plastic.  The plantage of the strue and correct to the best of its lepleteness and accuracy of data in this form because it has been mation is often protected from disclosure as trade secrets and sided only as estimates of the average weight of these parts and opants, metals, and non-metal materials contained within silicon pochip Technology Incorporated does not provide any warranty, anties provided by Microchip Technology Incorporated and its sations, sales order acknowledgement, and invoices.	nal design contro ubstance is NOT , there is no credi ory scheme work ity standard for p ss/ made from polyvi form concerning mowledge and be compiled based of some information the average weig devices (silicon express or implie subsidiaries are co	an intentional ingredient in the semiconductor device and, ble reason to believe that the unavoidable impurity concert-wide.  lastics. You can access the UL iQTM family of databases to myl chloride (PVC) plastic. "Window envelopes" used to how substances restricted by RoHS in Microchip Technology In lifef, as of the date listed in this form. Microchip Technolog on the ranges provided in Material Safety Data Sheets proving the total provided by subcontract assemblers a ht of anticipated significant toxic metals components. The IC) in the finished parts.  d, with respect to the information provided in this declarat ontained in Microchip's standard terms and conditions of some provided in Microchip's standard terms and conditions of some provided in Microchip's standard terms and conditions of some provided in Microchip's standard terms and conditions of some provided in Microchip's standard terms and conditions of some provided in Microchip's standard terms and conditions of some provided in Material Content Declarations (MCD) or indeptor in Material Content Declarations (MCD) or indeptor in the provided in Material Content Declarations (MCD) or indeptor in the provided in Material Content Declarations (MCD) or indeptor in the provided in Material Content Declarations (MCD) or indeptor in the provided in Material Content Declarations (MCD) or indeptor in the provided in Material Content Declarations (MCD) or indeptor in the provided in Material Content Declarations (MCD) or indeptor in the provided in the provi	tration of the obtain a test obtain a test obtain a test of the packing occuporated is y incorporated ided by raw mind raw materise estimates do ion. The exclusiale. These are ect or indirect or indirect	report at slip on the outline of cannot guaraterial supplie al suppliers. In o not include sive, limited pi provided in M	uter box and or devices in antee the ers. Supplier afformation is trace levels roduct flicrochip's		(mg) Total  Copper  Palladium  (mg) Total	Total  Wire Bond - Copper, palladium coated (CuPd)  7440-50-8  7440-05-3  Total  Plating on external leads (pins) - Matte Tin / annealed at 150°C for 1 hour	100.00 % of Total Weight 98.25 1.75 100.00 % of Total Weight	1.25

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